IN THE CLAIMS

Please amend claims 1-26.

Please enter the pending claims as follows:

- 1 1. (Currently Amended) A broad-angle multilayer (ML) mirror
- 2 comprising a multiple layer structure <u>over a substrate</u> to provide uniform
- 3 reflectivity over a wide range of incident angles with small phase shifts, the
- 4 <u>multiple layer</u> structure comprising 36 bi-layers wherein with an extra thick layer
- 5 of Molybdenum next to the substrate has a thickness of 2.4 11.3 nm and Silicon
- 6 has a thickness of 3.5 10.4 nm.
- 1 2. (Currently Amended) The <u>broad-angle</u> ML mirror of claim 1 wherein
- 2 the ML-mirror multiple layer structure provides an acceptance angle in excess of
- 3 20° without a significant loss of reflectivity.
- 1 3. (Currently Amended) The <u>broad-angle</u> ML mirror of claim 2 wherein
- 2 the loss of reflectivity is approximately 17%.

- 1 4. (Currently Amended) The broad-angle ML mirror of claim 1 wherein
- 2 the ML mirror multiple layer structure increases the relative small phase shifts
- 3 shift.
- 5. (Currently Amended) The broad-angle ML mirror of claim 1 wherein
- 2 the ML mirror multiple layer structure reflects light comprising comprises a
- 3 13.5nm central wavelength.
- 6. (Currently Amended) The broad-angle ML mirror of claim 1 wherein
- the multiple layer structure comprises: Molybdenum having a thickness of 2.4-
- 3 11.3 nm alternating with Silicon having a thickness of 3.5-10.4 nm in the bi-layers
- 4 a 13.5nm central wavelength.
- 7. (Currently Amended) The <u>broad-angle</u> ML mirror of claim 1 wherein
- 2 each of the bi-layers in the <u>multiple layer</u> structure <u>has</u> have a variable thickness.
- 8. (Currently Amended) The broad-angle ML mirror of claim 1 wherein
- the <u>multiple layer</u> structure <u>further comprises</u> an extra thick layer of Silicon near
- 3 the substrate includes additional bi-layers.

- 9. (Currently Amended) The broad-angle ML mirror of claim 8 wherein the
- 2 extra thick layer of Molybdenum is in bi-layer no. 1 additional bi-layers in the
- 3 structure are comprised of Mo/Si bi layers.
- 1 10. (Currently Amended) The broad-angle ML mirror of claim 8 wherein
- the extra thick layer of Silicon is in bi-layer no. 3 additional bi-layers in the
- 3 structure have a variable thickness.
- 1 11. (Currently Amended) An optical system having an extreme ultra-
- violet (EUV) radiation source, the optical system comprising:
- 3 a mask;
- 4 a wafer; and
- 5 a plurality of reflecting surfaces for imaging the mask on the wafer,
- 6 wherein one or more of the plurality of reflecting surfaces includes a broad-angle
- 7 multilayer (ML) mirror having a multiple layer structure over a substrate to
- 8 provide uniform reflectivity over a wide range of incident angles with small
- 9 phase shifts, the broad-angle ML mirror comprising 36 bi-layers wherein with an
- 10 extra thick layer of Molybdenum next to the substrate has a thickness of 2.4-
- 11 11.3 nm and Silicon has a thickness of 3.5 10.4 nm.

- 1 12. (Currently Amended) The optical system of claim 11 wherein the
- 2 plurality of reflecting surfaces comprises six mirrors.
- 1 13. (Currently Amended) The optical system of claim 11 wherein the
- 2 broad-angle ML mirror provides an acceptance angle in excess of 20° without a
- 3 significant loss of reflectivity.
- 1 14. (Currently Amended) The optical system of claim 13 wherein the ML
- 2 mirror has a loss of reflectivity of is approximately 17%.
- 1 15. (Currently Amended) The optical system of claim 11 wherein the
- 2 broad-angle ML mirror increases the small relative phase shifts shift.
- 1 16. (Currently Amended) The optical system of claim 11 wherein the
- 2 broad-angle ML mirror reflects light comprising comprises a 13.5 nm central
- 3 wavelength.
- 1 17. (Currently Amended) The optical system of claim 11 wherein the
- 2 structure broad-angle ML mirror comprises: Molybdenum having a thickness of
- 3 2.4-11.3 nm alternating with Silicon having a thickness of 3.5-10.4 nm in the bi-
- 4 layers a 13.5nm central wavelength.

- 1 18. (Currently Amended) The system of claim 11 wherein each of the bi-
- 2 layers has have a variable thickness.
- 1 19. (Currently Amended) The system of claim 11 wherein the structure
- 2 broad-angle mirror includes more than thirty-six bi-layers.
- 1 20. (Currently Amended) An optical system having an extreme ultra-
- violet (EUV) radiation source, the system comprising:
- 3 a mask;
- 4 a wafer; and
- 5 a plurality of reflecting surfaces for imaging the mask on the wafer,
- 6 including:
- 7 a <u>broad-angle</u> mirror having a multiple layer structure <u>over a substrate</u> to
- 8 provide uniform reflectivity over a wide range of angles with small phase shifts,
- 9 the broad-angle mirror comprising 36 bi-layers wherein with an extra thick layer
- 10 of Molybdenum next to the substrate has a thickness of 2.4-3.7 nm except for a
- thicker bi layer 1 nearest substrate and Silicon has a thickness of 3.5—4.1 nm
- 12 except for thicker bi-layers 3, 5, and 15.
- 13

- 1 21. (Currently Amended) The optical system of claim 20 wherein the
- 2 broad-angle mirror provides an acceptance angle in excess of 20° without a
- 3 significant loss of reflectivity.
- 1 22. (Currently Amended) The optical system of claim 21 wherein the
- 2 mirror has a loss of reflectivity of is approximately 17%.
- 1 23. (Currently Amended) The optical system of claim 20 wherein the
- 2 broad-angle mirror reflects light comprising comprises a 13.5nm central
- 3 wavelength.
- 1 24. (Currently Amended) The optical system of claim 20 wherein the
- 2 <u>broad-angle mirror structure further comprises: an extra thick layer of Silicon</u>
- 3 near the substrate a 13.5nm central wavelength.
- 1 25. (Currently Amended) The optical system of claim 20 wherein each of
- 2 the bi-layers have has a variable thickness.
- 1 26. (Currently Amended) The system of claim 20 wherein the broad-
- 2 angle mirror structure includes more than thirty-six bi-blayers.